

M. TECH.-III (ELECTRONICS V.L.S.I.) (CBCS – 2015 COURSE) :
WINTER - 2017
SUBJECT : ELECTIVE – 2 : TESTING AND VERIFICATION OF VLSI DESIGN

Day : **Thursday**
Date : **18/01/2018**

W-2017-2882

Time : **11.00 AM TO 02.00 PM**
Max. Marks : 60

N. B. :

- 1) All questions are **COMPULSORY**.
- 2) Figures to the right indicate **FULL** marks.
- 3) Answers to both the sections should be written in the **SEPARATE** answer books.
- 4) Assume suitable data, if necessary.

SECTION - I

Q.1 How will you define verification? How formal verification is performed? **(10)**
Discuss in brief.

OR

How verification is related to design reuse? Discuss testing v/s verification. **(10)**

Q.2 How static tool helps in verification? Explain with suitable example. **(10)**

OR

Differentiate Event v/s Cycle based simulators. **(10)**

Q.3 What is the purpose of unit level testing? How it is performed? **(10)**

OR

What are the verification strategies? **(10)**

SECTION – II

Q.4 What are the logical fault models? Explain in brief. **(10)**

OR

Discuss fault detection and fault dominance. **(10)**

Q.5 Describe in brief: Test generation for sequential circuits. **(10)**

OR

How testable combinational logic circuits are designed? **(10)**

Q.6 Explain Ad-hoc design with respect to testing. **(10)**

OR

How BIST is implemented? **(10)**

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